

Features and Benefits

- ❑ Programmable Sensor Interface IC with 4 to 20 mA current loop output
- ❑ Power supply from 6 to 35V_{DC}
- ❑ External or internal temperature sensor for compensating temperature errors

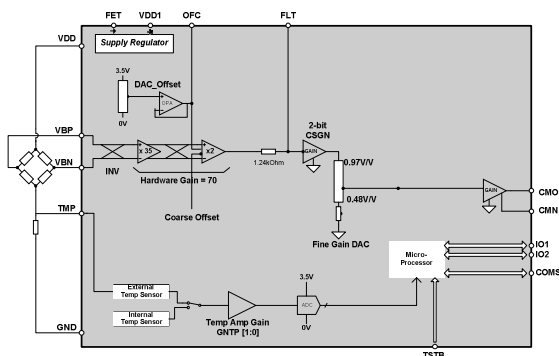
Application Examples

- ❑ Industrial pressure transducers.
- ❑ Strain gauges, accelerometers, position sensors, etc.
- ❑ Any bridge type sensor with current loop output.

Ordering Information

Part No.	Temperature Code	Package Code
MLX90323	K (-40C to 125C)	DF (SOIC16w)

1 Functional Diagram



2 General Description

The IC converts small changes of output voltage of full Wheatstone resistive bridge (caused by mechanical stimulus such as pressure, force, torque, light or magnetic field) to large changes of the IC output current. It removes parasitic DC level (Offset) from the output bridge voltage and amplifies this signal certain times (Gain). Offset and Gain are temperature dependant, so IC allows temperature compensation of bridge parasitic DC shift and sensitivity. Temperature can be measured either by internal or external (resistor) temperature sensor. Values of Offset and Gain and their temperature dependency are gotten during calibration process than stored in IC EEPROM as long as some other parameters. Special calibration mode allows easy end quick calibration process.

The IC has industry standard 4 – 20 mA current loop output interface and takes power directly from 2-wire signal line. IC works properly over wide voltage range (from 6 to 35 V) at the signal line.

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3 Glossary of Terms

CM	Current Mode
CMN	Current Mode Negative (supply connection)
CMO	Current Output
COMS	Communication, Serial
CR	Carriage Return
CSGN	Coarse Gain
CSOF	Coarse Offset
DACFnew	Filtered DAC value, new
DACFold	Filtered DAC value, old
DARDIS	DAC Resistor Disable
EOC	End Of Conversion flag bit
ETMI	Timer Interrupt Enable
ETPI	Enable Temperature Interrupt
FET	Field Effect Transistor
FG	Fixed Gain
FLT	Filter Pin
GNO	Gain and Offset adjusted digitized signal
GNOF	Gain, Offset
GNTF	Temperature Gain / Offset Coarse adjustment
HS	Hardware / Software limit
IFIX	fixed current output value
IINV	input signal invert command bit
ILIM	current limit
MODSEL	Mode Select
MUX	multiplexer
OFC	Offset Control
PLL	Phase Locked Loop
POR	Power On Reset
RX	receive
SAR	Successive Approximation Register
STC	start A/D conversion
Tdiff	temperature difference
Text	temperature, external
TMI	timer Interrupt
TMP	temperature signal
TPI	temperature interrupt
Tref	temperature reference
TSTB	test mode pin
TX	transmit
UART	Universal Asynchronous Receiver / Transmitter
VBN	bridge, positive, input
VBP	bridge, negative, input
V _{DD}	supply voltage
WCB	warn / cold boot
WDC	watch dog counter

4 Absolute Maximum Ratings

Table 1. Absolute Maximum Ratings

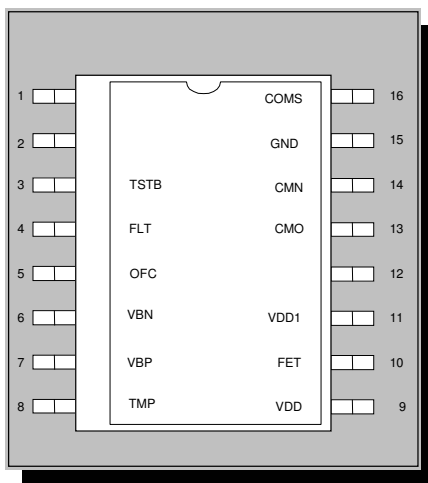
Supply voltage V_{DD} Max	6V
Supply voltage V_{DD} Min	4.5V
Supply voltage (operating), V_{DD1} Max	35V
Reverse voltage protection	-0.7V
Output current, I	8mA
Output current (short to V_{DD}), I	100mA
Output current (short to V_{SS}), I	8mA
Power dissipation, P_D	71mW
Operating temperature range, T_A	-40 to +125°
Storage temperature range, T_S	-55 to +150°C
Maximum junction temperature, T_J	150°C

Exceeding the absolute maximum ratings may cause permanent damage. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5 Pin Definitions and Descriptions

Table 2. Pin Description

Pin	Signal Name	Description
1,2	Unused	
3	TSTB	Test pin for Melexis production testing. (in normal application connected to VDD)
4	FLT	Filter pin; allows for connection of a capacitor to the internal analog path.
5	OFC	Offset control output. Provides access to the internal programmed offset control voltage for use with external circuitry. (unconnected when not used)
6,7	VBN,VBP	Bridge inputs, negative and positive.
8	TMP	Temperature sensor input. An external temperature sensor can be used in conjunction with the internal one. The external sensor can provide a temperature reading at the location of the bridge sensor.
9	V _{DD}	Regulated supply voltage. Used for internal analog circuitry to ensure accurate and stable signal manipulation.
10	FET	Regulator FET gate control. For generating a stable supply for the bridge sensor and internal analog circuitry (generates regulated voltage for VDD).
11	V _{DD1}	Unregulated supply voltage. Used for digital circuitry and to generate FET output.
12	NC	Do not connect
13	CMO	Current output.
14	CMN	Current negative rail. Current return path.
15	GND	Power supply return.
16	COMS	Serial communications pin. Bi-directional serial communication signal for reading and writing to the EEPROM.



6 General Electrical Specifications

Table 3. MLX90323 Electrical Specifications						
DC operating parameters: $T_A = -40$ to 125°C , $V_{DD1} = 6$ to $35V_{DC}$ (unless otherwise specified).						
Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Regulator & Consumption						
Input voltage range	V_{IN}	V_{DD1} (Regulator connected)	6		35	V
Supply current	I_{DD}	@ $T_A = 100^{\circ}\text{C}$ Current Mode		2.1		mA
Regulated supply voltage	V_{REG}		4.5	4.75	5.2	V
Regulated voltage temperature coefficient				-600		$\mu\text{V} / ^{\circ}\text{C}$
Supply rejection ratio	PSRR	$V_{DD1} > 6\text{V}$	90			dB
Instrumentation Amplifier						
Differential input range	VBP-VBN	IINV = 0	-2.88		8.38	$\text{mV}/V_{(VDD)}$
Differential input range	VBP-VBN	IINV = 1	-8.38		2.88	$\text{mV}/V_{(VDD)}$
Common mode input range		$1/2(VBP+VBN)$	38.0		65.0	%VDD
Common mode rejection Ratio	CMRR		60			dB
Hardware gain			69		84	V/V
Coarse offset control Range		CSOF[1:0] = 00	-4.37		-3.97	mV/V
		CSOF[1:0] = 01	-1.46		-1.09	mV/V
		CSOF[1:0] = 10	1.09		1.46	mV/V
		CSOF[1:0] = 11	3.97		4.37	mV/V
Fixed offset control range		High	1.71		2.29	mV/V
		Low	-2.00		-1.43	mV/V
IA chopper frequency				300		kHz
Gain Stage						
Coarse gain		CSGN = 000	3.0		3.3	V/V
	(Fixed Gain = 1023)	CSGN = 001	4.9		5.4	V/V
Coarse gain		CSGN = 010	8.0		8.8	V/V
Coarse gain		CSGN = 011	12.8		14.1	V/V
Fixed gain control range			0.480		0.970	V/V
Current Coarse Gain Stage						

Coarse Gain	CSGN = 00	1.05		1.17	V/V
	CSGN = 01	1.71		1.89	V/V
	CSGN = 10	2.77		3.06	V/V
	CSGN = 11	4.48		4.95	V/V
Current Output Stage					
Fixed gain	R _{SENSE} = 24 ohm	8.4		9.3	mA/V
Output current CMO pin	Current mode		27		mA
Current sense resistor			24		Ohms
Signal Path (General)					
Overall gain	Current sense res = 24Ω	284		2625	mA/V
Overall non-linearity		-0.25		0.25	%
Bandwidth (-3dB)	39 nF (FLT to GND)	2.8	3.5	4.2	KHz
Temperature Sensor & Amplifier					
Temperature sensor sensitivity			390		uV/°C
Temperature sensor output voltage		70		380	mV
Input voltage range TMP pin	GNTTP[1,0] = 00	207		517	mV
@ V _{DD} = 5.0V	GNTTP[1,0] = 01	145		367	mV
	GNTTP[1,0] = 10	101		263	mV
	GNTTP[1,0] = 11	71		186	mV
DAC					
Resolution			10		Bit
Monotonicity		Guaranteed By Design			
Offset Error			10		LSB
ADC					
Resolution			10		Bit
Monotonicity		Guaranteed by design			
Offset error			10		LSB
On-Chip RC Oscillator and Clock					
Trimmed RC oscillator frequency		86.9	87.8	88.7	kHz
Frequency temperature coefficient			26		Hz/°C
Clock Stability with temperature compensation over full temperature range		-3		+3	%
Ratio of f (microcontroller main clock and (RC oscillator)	TURBO = 0		7		
	TURBO = 1		28		

UART & COMS Pin					
UART baud rate	TURBO = 0		2400		Baud
	TURBO = 1		9600		Baud
COMS pin input levels	Low	$0.3 \cdot V_{DD}$			V
	High			$0.7 \cdot V_{DD}$	V
COMS Pin Output Resistance	Low		100		Ohms
	High		100		kOhms

7 Detailed General Description

7.1 Understanding 4-20 mA current loop interface

MLX90323 IC is optimized for 4 - 20 mA industry standard current loop interface. The 4 - 20mA current loop shown in Figure 1 is a common method of transmitting sensor information in many industrial applications. Transmitting sensor information via a current loop is particularly useful when the information has to be sent to a remote location over long distances. The loop operation is straightforward: a sensor's output voltage is first converted to a proportional current, with 4mA normally representing the sensor's zero-level output, and 20mA representing the sensor's full-scale output. Then, a receiver at the remote end converts the 4-20mA current back into a voltage which in turn can be further processed by a controller module.

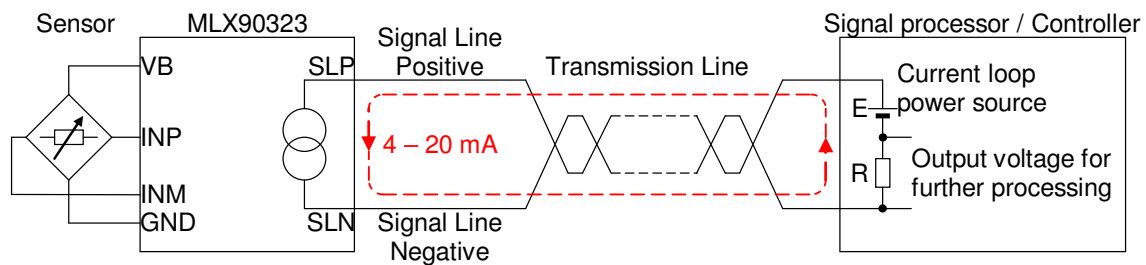


Figure 1. Current loop interface diagram

7.2 Analog features

Supply Regulator

A bandgap-stabilized supply-regulator is on-chip while the pass-transistor is external. The bridge-type sensor is typically powered by the regulated supply (typically 4.75V).

Oscillator

The MLX90323 contains a programmable on-chip RC oscillator. No external components are needed to set the frequency (87.8 kHz +/-1%). The MCU-clock is generated by a PLL (phase locked loop tuned for 614 kHz or 2.46 Mhz) which locks on the basic oscillator.

The frequency of the internal clock is stabilized over the full temperature range, which is divided into three regions, each region having a separate digital clock setting. All of the clock frequency programming is done by Melexis during final test of the component. The device uses the internal temperature sensor to determine which temperature range setting to use.

Power-On Reset

The Power-On Reset (POR) initializes the state of the digital part after power up. The reset circuitry is completely internal. The chip is completely reset and fully operational 3.5 ms from the time the supply crosses 3.5 volts. The POR circuitry will issue another POR if the supply voltage goes below this threshold for 1.0 us.

Test Mode

For 100% testability, a "TEST" pin is provided. If the pin is pulled low, then the monitor program is entered and the chip changes its functionality. In all other applications, this pin should be pulled high or left floating (internal pull-up).

Temperature Sense

The temperature measurement, TPO, is generated from the external or internal temperature sensor. This is converted to a 10-bit number for use in calculating the signal compensation factors. A 2-bit coarse adjustment GNTTP[1:0] is used for the temperature signal gain & offset adjustment.

7.3 Digital features

Microprocessor, LX11 Core, Interrupt Controller, Memories

The LX11 microcontroller core is described in its own datasheet. As an overview, this implementation of the LX11 RISC core has following resources:

Two accumulators, one index and two interrupt accumulators.

15 - 8 bit I/O ports to internal resources.

64 byte RAM.

4 kbytes ROM : 3 kbytes is available for customer's application firmware. 1k is reserved for test.

48 x 8 bit EEPROM.

Four interrupt sources, two UART interrupts and two timers.

UART

The serial link is a potentially full-duplex UART. It is receive-buffered, in that it can receive a second byte before a previously received byte has been read from the receiving register. However, if the first byte is not read by the time the reception of the second byte is completed, the first byte will be lost. The UART's baud rate depends on the RC-oscillator's frequency and the "TURBO"-bit (see output port). Transmitted and received data has the following structure: start bit = 0, 8 bits of data, stop bit = 1.

Sending Data

Writing a byte to port 1 automatically starts a transmission sequence. The TX Interrupt is set when the STOP-bit of the byte is latched on the serial line.

Receiving Data

Reception is initialized by a 1 to 0 transition on the serial line (i.e., a START-bit). The baud rate period (i.e., the duration of one bit) is divided into 16 phases. The first six and last seven phases of a bit are not used. The decision on the bit-value is then the result of a majority vote of phase 7, 8 and 9 (i.e., the center of the bit).

Spike synchronization is avoided by de-bouncing on the incoming data and a verification of the START-bit value. The RX Interrupt is set when the stop bit is latched in the UART.

Timer

The clock of the timers TMI and TPI is taken directly from the main oscillator. The timers are never reloaded, so the next interrupt will take place 2x oscillator pulses after the first interrupt.

Watch Dog

An internal watch dog will reset the whole circuit in case of a software crash. If the watch dog counter is not reset at least once every 26 milliseconds (@ 2.46 MHz main clock), the microcontroller and all the peripherals will be reset.

Temperature Processing

Temperature reading controls the temperature compensation. This temperature reading is filtered as designated by the user. The filter adjusts the temperature reading by factoring in a portion of the previous value. This helps to minimize the effect of noise when using an external temperature sensor. The filter equation is:

$$\begin{aligned} &\text{If measured_temp} > \text{Temp_f}(n) \text{ then} \\ &\quad \text{Temp_f}(n+1) = \text{Temp_f}(n) + [\text{measured_temp} - \text{Temp_f}(n)] / [2^{n_factor}] \\ &\text{If measured_temp} < \text{Temp_f}(n), \text{ then} \end{aligned}$$

$$\text{Temp_f}(n+1) = \text{Temp_f}(n) - [\text{measured_temp} - \text{Temp_f}(n)] [2^{-N_factor}]$$

Temp_f(n+1) = new filtered temperature value
 Temp_f(n) = previous filtered temperature value
 Measured_temp = Value from temperature A to D
 N_factor = Filter value set by the user (four LSB's of byte 25 of EEPROM), range 0-6.

The filtered temperature value, Temp_f, is stored in RAM bytes 58 and 59. The data is a 10 bit value, left justified in a 16 bit field.

7.4 Parameters calculation

The parameters OF and GN represent, respectively, offset correction and span control, while OFTCi and GNTCi represent their temperature coefficients (thermal zero shift and thermal span shift). After reset, the firmware continuously calculates the offset and gain DAC settings as follows: The EEPROM holds parameters GN, OF, OFTCi and GNTCi, where "i" is the gap number and can be $1 \leq i \leq 4$. The transfer function is described below.

$$V_{out} = FG * DAC_GAIN * CSGN[2:0] * \{V_{in} + DAC_OFFSET + CSOF\}$$

$$I_{out} = FG * DAC_GAIN * CSGN[1:0] * \{V_{in} + DAC_OFFSET + CSOF\} * 8.85 \text{mA/V}$$

FG = Hardware Gain (~72V/V). Part of the hardware design, and not changeable

CSGN = Course Gain, part of byte 2 in EEPROM.
 CSOF = Coarse Offset, part of byte 2 in EEPROM.

GAIN

$$DAC_GAIN \text{ (new value)} \sim GN[9:0] + [GNTCi * dT]$$

GN[9:0] = Fixed Gain, bytes 3 and 17 in EEPROM.

GNTCi = Gain TC for a given temperature segment i. GNTCiL and GNTCiH in EEPROM table.

dT = Temp. change within the appropriate gap

How to calculate gain in the first temp. gap?:

$$DAC_GAIN = GN[9:0] - GNTC1 * (T1 - \text{Temp_f1})$$

How to calculate gain in the other temp. gaps?:

$$\text{2nd gap: } DAC_GAIN = GN[9:0] + GNTC2 * (\text{Temp_f2} - T1)$$

$$\text{3rd gap: } DAC_GAIN = DAC_GAIN2 + GNTC3 * (\text{Temp_f3} - T2)$$

$$\text{4th gap: } DAC_GAIN = DAC_GAIN3 + GNTC4 * (\text{Temp_f4} - T3)$$

Where:

Temp_f = Filtered temp (previously described)

If GNTC1 > 2047 => DAC_GAIN ↑

If GNTC2,3,4 > 2047 => DAC_GAIN ↓

[V/V]

$$(0.97 - 0.48) * \frac{GN[9:0]}{1023} + 0.48 = DAC_GAIN$$

OFFSET

$$DAC_OFFSET \text{ (new value)} \sim OF[9:0] + [OFTCi * dT]$$

OF[9:0] = Fixed Gain, bytes 4 and 17 in EEPROM.

OFTCi = Offset for a given temperature segment I. OFTCiL and OFTCiH in EEPROM table.

dT = Temp. change within the appropriate gap.

Calculation of the offset for a given temperature segment is performed the same way as for the gain.

$$(1.83 - -1.57) * \frac{OF[9:0]}{1023} - 1.57 = DAC_OFFSET \quad [mV/V]$$

7.5 Communications

The MLX90323 firmware transfers a complete byte of data into and from the memory based on a simple command structure. The commands allow data to be read and written to and from the EEPROM and read from the RAM. RAM data that can be read includes the current digitized temperature and digitized GNO. The commands are described below. Melexis provides setup software for programming the MLX90323.

UART Commands

The commands can be divided into three parts: (1) downloading of data from the ASIC, (2) uploading of data to the ASIC and (3) the reset command.

All the commands have the same identification bits. The two MSB's of the sent byte indicate the command while the last six MSB's designate the desired address. The commands are coded as followed:

11 to read a RAM byte.

10 to read an EEPROM byte.

01 to write in the EEPROM.

00 to write in the RAM.

The addresses can include 0-63 for the RAM, 0-47 for the EEPROM, and 63 for the EEPROM, RESET Command (read).

Downloading Command

With one byte, data can be downloaded from the ASIC. The ASIC will automatically send the value of the desired byte.

Uploading Command

Writing to the RAM or EEPROM involves a simple handshaking protocol in which each byte transmitted is acknowledged by the firmware. The first byte transmitted to the firmware includes both command and address. The firmware acknowledges receipt of the command and address byte by echoing the same information back to the transmitter. This "echo" also indicates that the firmware is ready to receive the byte of data to be stored in RAM or EEPROM. Next, the byte of value to be stored is transmitted and, if successfully received and stored by the firmware, is acknowledged by a "data received signal," which is two bytes of value BCh. If the "data received signal" is not observed, it may be assumed that no value has been stored in RAM or EEPROM.

Reset Command

Reading the address 63 of the EEPROM resets the ASIC and generates a received receipt indication. Immediately before reset, the ASIC sends a value of BCh to the UART, indicating that the reset has been received.

EEPROM Data

All user-settable variables are stored in the EEPROM within the MLX90323. The EEPROM is always re-programmable. Changes to data in the EEPROM do not take effect until the device is reset via a soft reset or power cycle. 12 bit variables are stored on 1.5 bytes. The 4 MSB's are stored in a separate byte and shared with the four MSB's of another 12-bit variable.

Clock Temperature Stabilization

To provide a stable clock frequency from the internal clock over the entire operating temperature range, three separate clock adjust values are used. Shifts in operating frequency over temperature do not effect the performance but do, however, cause the communications baud rate to change.

The firmware monitors the internal temperature sensor to determine which of three temperature ranges the device currently is in. Each temperature range has a factory set clock adjust value, ClkTC1, ClkTC2, and ClkTC3. The temperature ranges are also factory set. The Ctemp1 and Ctemp2 values differentiate the three ranges. In order for the temperature A to D value to be scaled consistently with what was used during factory programming, the CLKgntp (temperature amplifier gain) valued is stored. The Cadj value stored in byte 1 of the EEPROM is used to control the internal clock frequency while the chip boots.

Unused Bytes

There are eight unused bytes in the EEPROM address map. These bytes can be used by the user to store information such as a serial number, assembly date code, production line, etc. Melexis doesn't guarantee that these bytes will be available to the user in future revisions of the firmware.

EEPROM Checksum

A checksum test is used to ensure the contents of the EEPROM. The eight bit sum of all of the EEPROM addresses should have a remainder of 0FFh when the checksum test is enabled (mode byte). Byte 47 is used to make the sum remainder totals 0FFh. If the checksum test fails, the output will be driven to a user defined value, Faultval. When the checksum test is enabled, the checksum is verified at initialization of RAM after a reset.

RAM Data

All the coefficients (pressure, temperature) are compacted in a manner similar to that used for the EEPROM. They are stored on 12 bits (instead of keeping 16 bits for each coefficient). All the measurements are stored on 16 bits. The user must have access to the RAM and the EEPROM, while interrupt reading of the serial port. Therefore, bytes must be kept available for the return address, the A-accu and the B-accu, when an interrupt occurs. The RAM keeps the same structure in the both modes.

Table 4. Examples of Fixed Point Signed Numbers

Decimal Value	Hexadecimal Equivalent	Fixed Point Signed Number Equivalent
0	0000h	+0.00
1023	3FFh	+0.9990234
1024	400h	+1.000
2047	7FFh	+1.9990234
2048	800h	-0.000
3071	0BFFh	-0.9990234

3072	0C00h	-1.000
4095	0FFFh	-1.9990234

Data Range

Various data are arranged as follows:

Temperature points: 10 bits, 0-03FF in high-low order.

Pressure points: 10 bits, 0-03FF in high-low order.

GN1: 10 bits, 0-03FF in high-low order.

OF1: 10 bits, 0-03FF in high-low order.

GNTCi: signed 12 bits (with MSB for the sign), [-1.9990234, +1.9990234].

OFTCi: signed 12 bits (with MSB for the sign), [-1.9990234, +1.9990234].

Table 5. EEPROM Byte Definitions

Byte	Designation	Note
0	Turbo mode, temp selection	Bit 1: (0 = internal temp, 1 = external temp) Bit 3: (0 = Turbo mode active, 1 = not active) Bit 0-2-4-5-6-7: unused
1	Cadj	Controls system clock during boot.
2	Coarse Control	Contents described in Table 6.
3	GN1L	The eight LSB's of the Fixed Gain, GN[7:0].
4	OF1L	The eight LSB's of Fixed Offset OF[7:0].
5	GNTC1L	The eight LSB's of the first gain TC GNTC1[7:0].
6	OFTC1L	The eight LSB's of the first offset TC OFTC1[7:0].
7	TR1L	The eight LSB's of the first temperature point, T1[7:0].
8	GNTC2L P5L	The eight LSB's of the second gain TC GNTC2[7:0]. The eight LSB's of Pressure Point 5 P5[7:0].
9	OFTC2L	The eight LSB's of the second offset TC OFTC2[7:0].
10	TR2L P4L	The eight LSB's of the second temperature point T2[7:0]. The eight LSB's of Pressure Point 4 (or Signature) P4[7:0].
11	GNTC3L	The eight LSB's of the third gain TC GNTC3[7:0].

Table 5. EEPROM Byte Definitions (continued)

Byte	Designation	Note
12	OFTC3L or P3L	The eight LSB's of the third offset TC OFTC3[7:0] The eight LSB's of Pressure Point 2 (or Signature) P2[7:0].
13	TR3L	The eight LSB's of the third temperature point T3[7:0].
14	GNTC4L or P2L	The eight LSB's of the fourth gain TC GNTC4[7:0]. The eight LSB's of Pressure Point 2 P2[7:0].
15	OFTC4L	The eight LSB's of the fourth offset TC OFTC4.
16	PoffL	The eight LSB's of Pressure (output signal) Ordinate Poff[7:0].
		Upper four bits Lower four bits
17	GN1[9:8] OF1[9:8]	Two MSB's of fixed gain GN[9:8]. Two MSB's of fixed offset OF[9:8]
18	GNTC1[11:8] OFTC1[11:8]	Four MSB's of first gain TC GNTC1[11:8]. Four MSB's of the first offset TC OFTC1[11:8].
19	TR1[9:8] GNTC2[11:8] P5[9:8]	Two MSB's, first temperature point T1[9:8] or Four MSB's, Pressure Four MSB's, second gain TC GNTC2[11:8] or TC GNTC2[11:8] or Two MSB's Pressure Point 5 P5[9:8].
20	OFTC2[11:8] TR2[9:8] P4[9:8]	Four MSB's second offset TC OFTC2[11:8] or Two MSB's second temperature point T2[9:8] or Two MSB's Pressure Point 4 P4[9:8].
21	GNTC3[11:8] OFTC3[11:8] P3[9:8]	Four MSB's third gain TC GNTC3[11:8] or Four MSB's third offset TC OFTC3[11:8] or Two MSB's Pressure Point 3 P3[9:8].
22	TR3[9:8] GNTC4[11:8] P2[9:8]	Two MSB's third temperature point t3[9:8] or Four MSB's fourth gain TC GNTC4[11:8] or Two MSB's Pressure Point 2 P2[9:8].
23	OFTC4[11:8] Poff[9:8]	Four MSB's fourth offset TC ordinate OFTC4[11:8] or Two MSB's Pressure Poff[9:8].

Table 5. EEPROM Byte Definitions (continued)

Byte	Designation	Note
24	PNB_TNB	Number of temperature and pressure gaps.
25	n_factor	Temperature filter coefficient, four LSB's. Four MSB's must all be zero.
26	Not used	This byte is not used.
32	ClkTC1	Value of Cadj at low temperature (Don't change; factory set).
33	ClkTC2	Value of Cadj at mid temperature (Don't change; factory set).
34	ClkTC3	Value of Cadj at high temperature Don't change; factory set).
35	Ctemp1	First Cadj temperature point, eight MSB's of the 10 bit internal temperature value (set at factory; do not change).
36	Ctemp2	Second Cadj temperature point, eight MSB's of the 10 bit internal temperature value (set at factory; do not change).
37-38	Not used	These bytes are not used and are available to the user.
39	CLKgntp	Setting for temperature amplifier for clock temperature adjustment temperature reading (factory set, do not change).
40-41	Faultval	Value sent to output if checksum test fails is a 10 bit value.
42-46	Not Used	These bytes are not used and are available to the user.
47	Checksum	EEPROM checksum; value needed to make all bytes add to 0FFh. Must be set by user if checksum test is active.

Table 6. Bit Definitions, Coarse Control , Byte 2

Bit	Symbol	Function
7	IINV	Invert signal sign.
6	Gntp1	Gain & offset of temperature amplifier.
5	Gntp0	Gntp = 0 to 3.
4	CSOF 1	Coarse offset of signal amplifier.
3	CSOF 0	CSOF = 0 to 3.
2	CSGN2	Coarse gain of signal amplifier. CSGN = 0 to 7. If CSGN > 3, output range = 0 to 10V. If CSGN <= 3, output range = 0 to 5V.
1	CSGN1	
0	CSGN0	

Table 7. RAM Byte Definitions

Byte	Functions	Remarks
0	Not used	
1	GN1L	Fixed gain number (8LSB).
2	OF1L	Fixed offset number (8LSB).
3	GNTC1L	First gain TC (8LSB).
4	OFTC1L	First offset TC (8LSB).
5	TR1L	First temperature point.
6	GNTC2L P5L	Second gain TC. Pressure point 5 (8LSB).
7	OFTC2L	Second offset TC.
8	TR2L P4L	Second temperature point. Pressure Point 4 (or Signature) (8LSB).
9	GNTC3L	Third gain TC.
10	OFTC3L P3L	Third offset TC. Pressure Point 2 (or Signature) (8LSB).

Byte	Functions	Remarks
11	TR3L	Third temperature point.
12	GNTC4L P2L	Fourth gain TC. Pressure Point 1 (8LSB).
13	OFTC4L	Fourth offset TC.
14	DIGMOP1L	Fixed pressure (8LSB).
15	GN1[9:8] OF1[9:8]	Two MSB's of fixed gain GN[9:8]. Two MSB's of fixed offset OF[9:8].
16	GNTC1 [11:8] OFTC1[11:8]	Four MSB's of first gain TC GNTC1[11:8]. Four MSB's of the first offset TC OFTC1[11:8]
17	TR1[9:8] GNTC2[11:8] P5[9:8]	Two MSB's, first temperature gain point T1[9:8] or Four MSB's, second TC GNTC2[11:8] or Two MSB's, Pressure Point 5 P5[9:8]
18	OFTC2[11:8] TR2[9:8] P4[9:8]	Four MSB's, second offset TC OFTC2[11:8] or Two MSB's, second temp. point T2[9:8] or Two MSB's, Pressure Point 4 P4[9:8].
19	GNTC3[11:8] OFTC3[11:8] P3[9:8]	Four MSB's, Third Gain TC GNTC3[11:8] or Four MSB's Third Offset TC OFTC3[11:8] or Two MSB's Pressure Point 3 P3[9:8]
20	TR3[9:8] GNTC4[11:8] P2[9:8]	Two MSB's, third temperature point t3[9:8] or Four MSB's, Fourth Gain TC GNTC4[11:8] or Two MSB's, Pressure Point 2 P2[9:8].
21	OFTC4[11:8] P1[9:8]	Four MSB's Fourth Offset TC OFTC4[11:8] or Two MSB's Pressure Point 1 P1[9:8].
22	PNB_TNB	Same as EEPROM.
23	N_Factor	Temperature filter coefficient — 4 LSB's, 4 MSB = 0
24	Not Used	
25-26	GN	Offset Ordinate of the current gap.
27-28	OF	Gain Ordinate of the current gap.
29	Taddress	4 bits for the max. temperature address of the current gap; 4 bits for the min. temperature address of the current gap.
35-36	A_16	16 bits A Register.
37-38	B_16	16 bits B Register.
39-42	RESULT_32	32 bits result (for 16 bit multiplication).

43-44	Tempo1	Measured temperature, internal or external, and temporary variable 1.
45	Tempo2	Temporary variable 2.
46-47	Signal_In	Digitized signal value, analog and digital mode
48	Coms_backup	Address saved when command is send.
49	P3_copy	Port 3 setting copy.
50	Adsav1	Address saved at interrupt.
51-52	Aaccsav	A-Accumulators saved at interrupt.
53	Baccsav	B-Accumulators saved at interrupt.
54-55	DAC_gain	DAC gain (GN).
56-57	DAC_offset	DAC offset (OF).
58-59	Temp_f	Filtered temperature. This is a 10 bit number that is left justified in a 16 bit field.
60-61	Signal_Out	Digitized linearity corrected signal value. Digital mode only.
62-63	Adsav2	Address saved when call.

Note: Because of space considerations, the measured temperature can't be kept in the RAM at all times. If the measured temperature is to be available, the temperature filter variable, N_Factor, must be set to 6.

8 Unique Features

Customization

Melexis can customize the MLX90323 in both hardware and firmware for unique requirements. The hardware design provides 64 bytes of RAM, 3 kbytes of ROM, and 48 bytes of EEPROM for use by the firmware.

Special Information

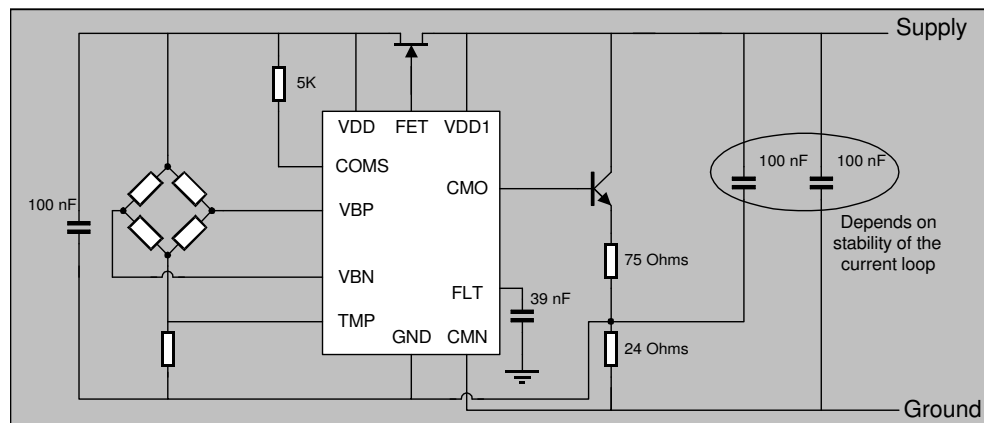
The output of the sensor bridge is amplified via offset and gain amplifiers and then converted to the correct output signal form in one of the output stages.

The sensitivity and offset of the analog signal chain are defined by numbers passed to the DAC interfaces from the microcontroller core (GN[9:0] and OF[9:0]). The wide range of bridge offset and gain is accommodated by means of a 2-bit coarse adjustment DAC in the offset adjustment (CSOF[1:0]), and a similar one in the gain adjustment (CSGN[2:0]). The signal path can be directed through the processor for digital processing.

Programming and Setup

The MLX90323 needs to have the compensation coefficients programmed for a particular bridge sensor to create the sensor system. Programming the EEPROM involves some minimal communications interface circuitry, Melexis setup software, and a PC. The communications interface circuitry is available in a development board. This circuitry communicates with the PC via a standard RS-232 serial communications port.

9 Application Information



10 Standard information regarding manufacturability of Melexis products with different soldering processes

Our products are classified and qualified regarding soldering technology, solderability and moisture sensitivity level according to following test methods:

Reflow Soldering SMD's (Surface Mount Device)s

- IPC/JEDEC J-STD-020
Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices (classification reflow profiles according to table 5-2)
- EIA/JEDEC JESD22-A113
Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing (reflow profiles according to table 2)

Wave Soldering SMD's (Surface Mount Device)s and THD's (Through Hole Device)s

- EN60749-20
Resistance of plastic- encapsulated SMD's to combined effect of moisture and soldering heat
- EIA/JEDEC JESD22-B106 and EN60749-15
Resistance to soldering temperature for through-hole mounted devices

Iron Soldering THD's (Through Hole Device)s

- EN60749-15
Resistance to soldering temperature for through-hole mounted devices

Solderability SMD's (Surface Mount Device)s and THD's (Through Hole Device)s

- EIA/JEDEC JESD22-B102 and EN60749-21
Solderability

For all soldering technologies deviating from above mentioned standard conditions (regarding peak temperature, temperature gradient, temperature profile etc) additional classification and qualification tests have to be agreed upon with Melexis.

The application of Wave Soldering for SMD's is allowed only after consulting Melexis regarding assurance of adhesive strength between device and board.

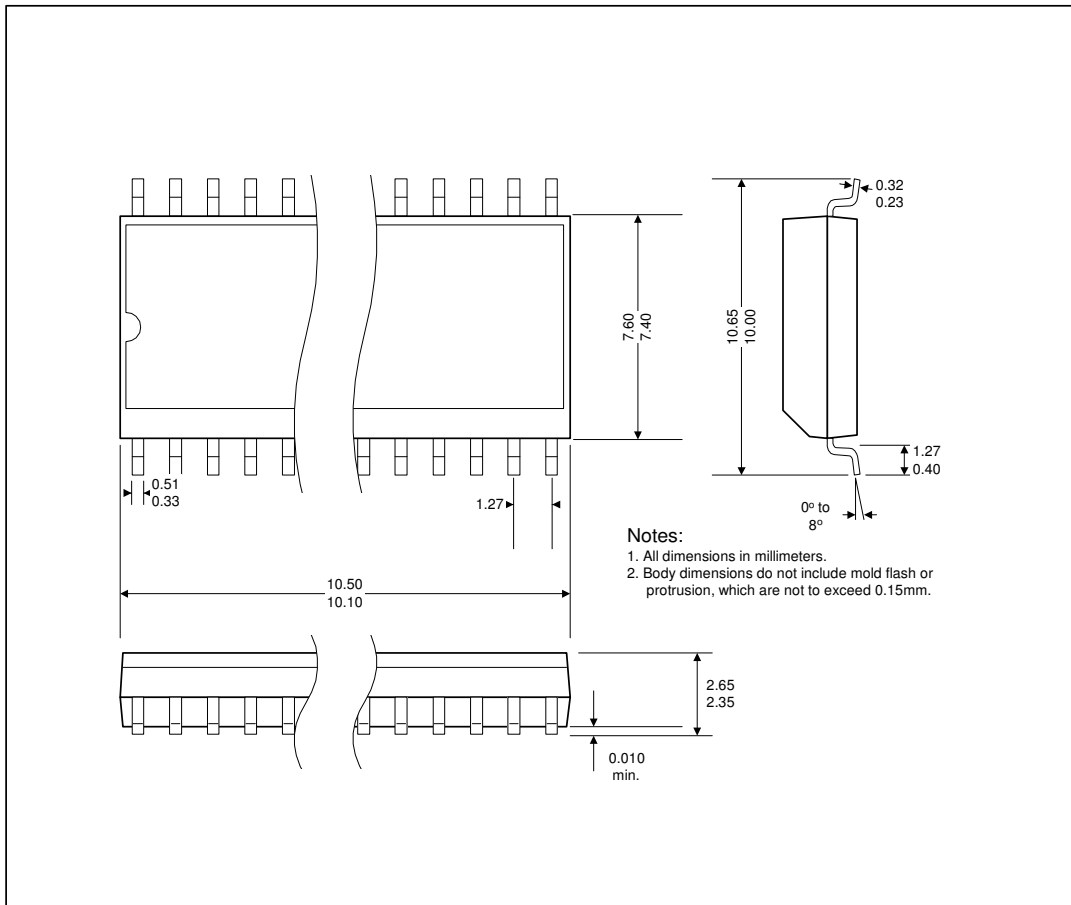
Melexis is contributing to global environmental conservation by promoting **lead free** solutions. For more information on qualifications of **RoHS** compliant products (RoHS = European directive on the Restriction Of the use of certain Hazardous Substances) please visit the quality page on our website:

<http://www.melexis.com/quality.asp>

11 ESD Precautions

Electronic semiconductor products are sensitive to Electro Static Discharge (ESD). Always observe Electro Static Discharge control procedures whenever handling semiconductor products.

12 Package Information



13 Disclaimer

Devices sold by Melexis are covered by the warranty and patent indemnification provisions appearing in its Term of Sale. Melexis makes no warranty, express, statutory, implied, or by description regarding the information set forth herein or regarding the freedom of the described devices from patent infringement. Melexis reserves the right to change specifications and prices at any time and without notice. Therefore, prior to designing this product into a system, it is necessary to check with Melexis for current information. This product is intended for use in normal commercial applications. Applications requiring extended temperature range, unusual environmental requirements, or high reliability applications, such as military, medical life-support or life-sustaining equipment are specifically not recommended without additional processing by Melexis for each application.

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